

ABSTRACT

X-RAY SCATTERING METHOD AND SYSTEM FOR NON-DESTRUCTIVELY INSPECTING BOND LINE AND POROSITY

Non-destructive inspection methods, systems, and apparatuses are disclosed for non-destructively inspecting a bond line, including a bond line present in a composite substrate and in adhesive material layers in a composite substrate, with the methods, systems, and apparatuses incorporating a small angle X-ray scattering array.

Fig. 1